

Integrated electron density for double gate MOS

Assignment #8

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In this assignment, we solve the Poisson equation by Newton-Raphson method. The figure 1 shows our sample structure.

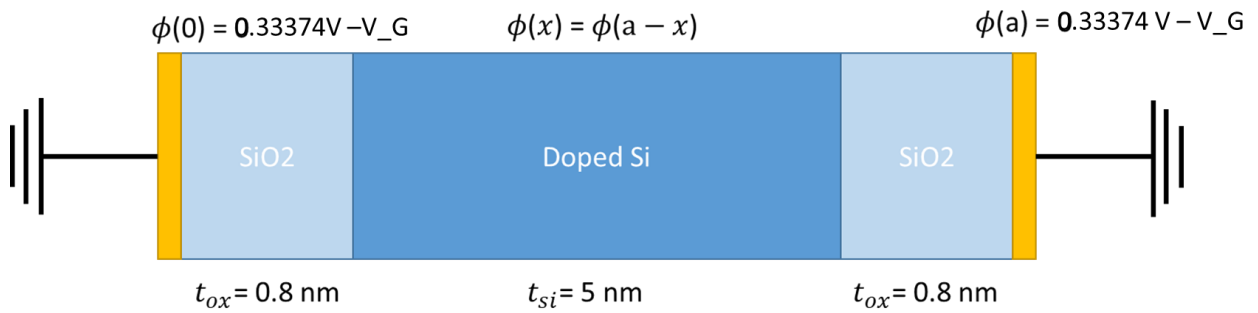


Figure 1. Schematic image for double gate MOS

For this assignment, the gate voltage varies from 0 to 1V. A electrostatic potential ϕ will be calculated first with respect to different gate voltage. Then, the electron density through the semiconducting layer will be calculated. Finally, we will get an integration of the electron density through the channel region.

To solve this problem by Newton-Raphson method, we should set the Jacobian matrix and residue vector carefully. The figure 2 shows the Jacobian and residue for my code.

$$J\delta\phi = -r$$

```

for ii = 2 : N-1
    %Laplacian part
    if (ii < j1 || ii > j2)
        res(ii,1) = eps_ox*phi(ii+1,gate) - 2*eps_ox*phi(ii,gate) + eps_ox*phi(ii-1,gate);
        Jaco(ii,ii-1) = eps_ox; Jaco(ii,ii) = -2*eps_ox; Jaco(ii,ii+1) = eps_ox;
    elseif (ii==j1)
        res(ii,1) = eps_si*phi(ii+1,gate) - (eps_si+eps_ox)*phi(ii,gate) + eps_ox*phi(ii-1,gate);
        Jaco(ii,ii-1) = eps_ox; Jaco(ii,ii) = -(eps_ox+eps_si); Jaco(ii,ii+1) = eps_si;
    elseif (ii==j2)
        res(ii,1) = eps_ox*phi(ii+1,gate) - (eps_si+eps_ox)*phi(ii,gate) + eps_si*phi(ii-1,gate);
        Jaco(ii,ii-1) = eps_si; Jaco(ii,ii) = -(eps_ox+eps_si); Jaco(ii,ii+1) = eps_ox;
    else
        res(ii,1) = eps_si*phi(ii+1,gate) - 2*eps_si*phi(ii,gate) + eps_si*phi(ii-1,gate);
        Jaco(ii,ii-1) = eps_si; Jaco(ii,ii) = -2*eps_si; Jaco(ii,ii+1) = eps_si;
    end
end
%charge part
for ii = j1:j2
    if(ii==j1)
        res(ii,1) = res(ii,1) - coef*(Nacc+ni*exp(phi(ii,gate)/V_T))+0.5;
        Jaco(ii,ii) = Jaco(ii,ii) - coef*ni*exp(phi(ii,gate)/V_T)/V_T+0.5;
    elseif (ii==j2)
        res(ii,1) = res(ii,1) - coef*(Nacc+ni*exp(phi(ii,gate)/V_T))+0.5;
        Jaco(ii,ii) = Jaco(ii,ii) - coef*ni*exp(phi(ii,gate)/V_T)/V_T+0.5;
    else
        res(ii,1) = res(ii,1) - coef*(Nacc+ni*exp(phi(ii,gate)/V_T));
        Jaco(ii,ii) = Jaco(ii,ii) - coef*ni*exp(phi(ii,gate)/V_T)/V_T;
    end
end

update = Jaco\(-res);
phi(:,gate) = phi(:,gate) + update;
end

```

Figure 2. Jacobian matrix and residue vectors

Once we get the all electrostatic potential, now we can calculate the electron density and integrated electron density. The figure 3 shows my code for electron densities.

```

for ii = j1:j2    %{ Semiconducting layer 에서 존재하는 carrier density %}
    elec(ii,gate) = ni*exp(phi(ii,gate)/V_T);
    if (ii==j1 || ii==j2)
        int_elec(gate,1) = int_elec(gate,1) + Deltax/2*elec(ii,gate);
    else
        int_elec(gate,1) = int_elec(gate,1) + Deltax/2*elec(ii,gate);
    end
end
end

```

%{ 경계에서의 적분이라
½를 곱해주었음 %}

Results

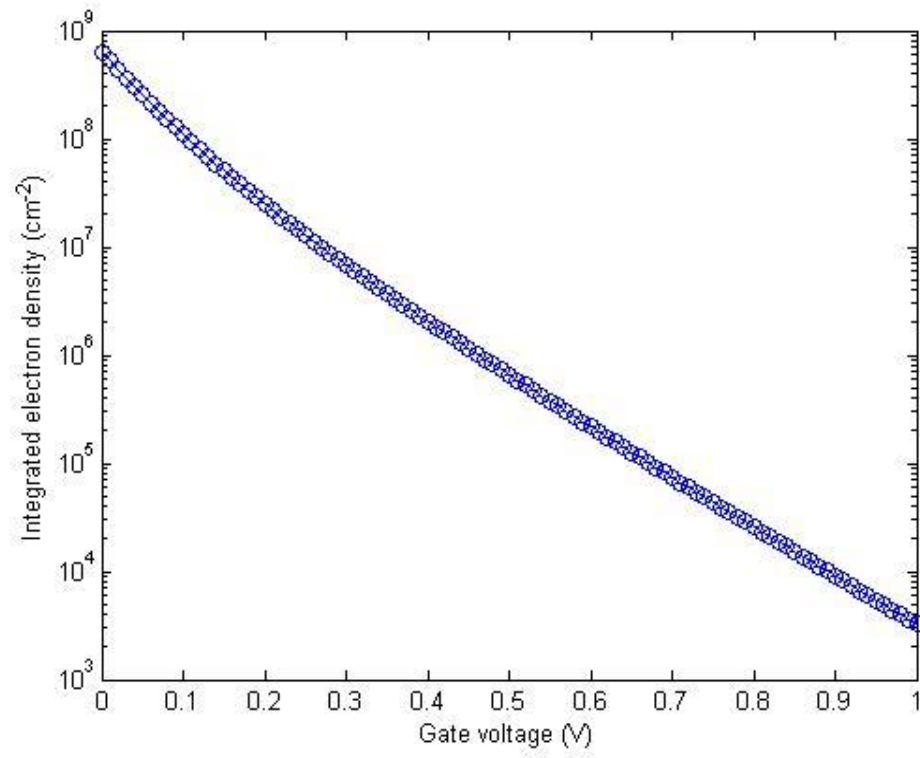


Figure 4 Integrated electron density – Gate voltage graph.